Electronic Supplementary Information Does interfacial exciton quenching exist in high-performance quantum dot light-emitting diodes?

Xiangwei Qu^{1,2}, Depeng Li^{1,2}, Wenbo Liu^{1,2}, Jingrui Ma^{1,2}, Mi Gu^{1,2}, Siqi Jia^{1,2}, Guohong Xiang^{1,2}

and Xiao Wei Sun^{1,2}

1 Institute of Nanoscience and Applications, Southern University of Science and Technology, Shenzhen 518055, China

2 Key Laboratory of Energy Conversion and Storage Technologies (Southern University of Science and Technology), Ministry of Education, Guangdong University Key Laboratory for Advanced Quantum Dot Displays and Lighting, Guangdong-Hong Kong-Macao Joint Laboratory for Photonic-Thermal-Electrical Energy Materials and Devices, Shenzhen Key Laboratory for Advanced Quantum Dot Displays and Lighting, and Department of Electrical and Electronic Engineering, Southern University of Science and Technology, Shenzhen 518055, China

Email: <u>sunxw@sustech.edu.cn</u>.



Figure. S1 EL spectrum of QLED



Figure. S2 (a) UPS spectrum of secondary-electron cutoff (left) and valence-band edge regions (right) of ZnMgO film, (b) $(\alpha hv)^2$ -hv plot converted from the ZnMgO absorption spectrum.

VBM and CBM of ZnMgO are estimated using the following equations:

 $VBM = E_{in} - (E_{cutoff} - E_{onset})$ $CBM = VBM + E_g$



Figure. S3 photos of pristine and encapsulated ZnMgO films excited by 330 nm Xe lamp



Figure. S4 TRPL characteristics of encapsulated QD and QD-ZnMgO films after they are exposed

to air for 5 minutes.



Figure. S5 TRPL characteristics of (a) pristine green QD, pristine and encapsulated green QD-ZnMgO films, and (b) pristine blue QD, pristine and encapsulated blue QD-ZnMgO films.



Fig. S6 TA and absorption spectra of QD.



Figure. S7 TA kinetics of pristine QD, pristine and encapsulated QD-ZnMgO films at first 10 ps.



Figure. S8 Normalized PL intensity of QD-ZnMgO film at 0 minutes and 30 minutes.



Figure. S9 Absorption intensity of (a) pristine and (b) encapsulated Q-ZnMgO films with a thickness of 20 µm over time.

Table S1 TRPL fitted data of QD and QD-ZnMgO films using double exponential decay

	A_1 (%)/ τ_1 (ns)	$A_2(\%) / \tau_2 (ns)$	τ (ns)
QD	55.52/14.19	44.48/30.11	21.11
QD-ZnMgO	45.61/6.80	54.39/17.63	12.70
Exciton lifetime is calculated by $\tau = \sum A_i \tau_i$			

Calculation of maximum EQE of QLED:

The EQE is described by

$$EQE = \eta_r \eta_{PL} \eta_{ex}$$

where η_r is the ratio of injected charges that form excitons in QD layer (also called charge balance factor), η_{PL} is the PLQY of QD film, η_{ex} is the light extraction efficiency. If we assume a near-unity charge balance factor (100%) and light out-coupling efficiency (20%-25%), considering a PLQY (50.2%) of QD-ZnMgO film, the maximum EQE of the QLED device should be 12.55%.

Instruction for the estimation of radiative transition rate and charge transfer rate :

The TA kinetics of pristine QD and encapsulated QD-ZnMgO films are fitted using a single exponential decay.

 $I = I_0 exp^{[ro]}(-\frac{t}{\tau_r})$

The TA kinetics of pristine QD-ZnMgO films is fitted by double exponential decay.

$$I = I_1 \exp\left(-\frac{t}{\tau_r}\right) + I_2 \exp\left(-\frac{t}{\tau_{CT}}\right)$$

The radiative transition rate is estimated to be $1/\tau_r$, the charge transfer rate is estimated to be $1/\tau_{CT}$.